Email : sales@scilabexport.com
Phone: +91-7082934803

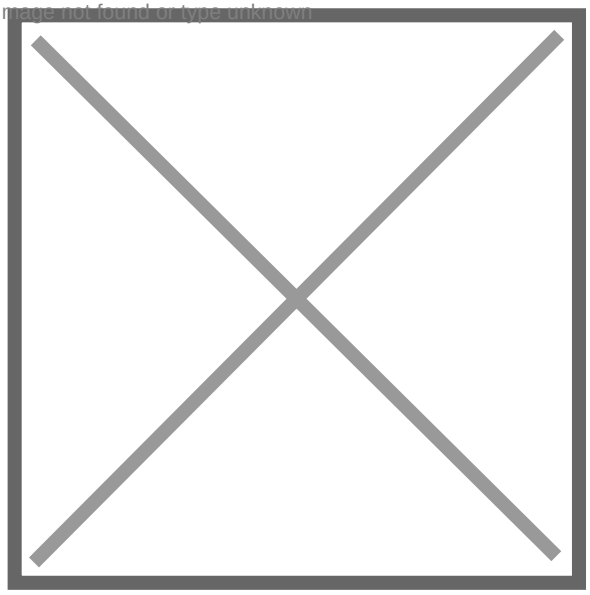
Product Name :

Fourier Transform Infrared Spectrometer (FTIR)

Product Code :

SCI-304/07

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Description :

Fourier Transform Infrared Spectrometer (FTIR) (Product Code: SCI-304/07) is a single-beam infrared spectrometer used to identify organic and inorganic materials from their infrared absorption spectra in research, quality-control and university laboratories. It measures from 7,800 to 350 cm-1 at a maximum resolution of 0.4 cm-1, using a sealed Michelson interferometer, a Ge/KBr beam splitter and a Peltier-controlled DLaTGS detector. It is supplied by **Jain Scientific Equipments Pvt Ltd (ScienceLab)**, Ambala, India, as one of the laboratory analytical instruments it offers.

Specifications

Parameter	Detail
Standard measurement range	7,800 to 350 cm-1
Display wavenumber range	15,000 to 0 cm-1 (standard)
Wavenumber accuracy	Within ± 0.01 cm-1 (theoretical value)
Maximum resolution	0.4 cm-1
Signal-to-noise ratio	35,000:1
Optical system	Single-beam optics; centre focus, light axis 70 mm high
Interferometer	Michelson type (listed at both 30° and 45° incident angle); corner cube mirror with auto-alignment, sealed structure, DSP control
Beam splitter	Germanium-coated KBr (Ge/KBr)
Light source	High-intensity (high-energy) ceramic source
Detector	DLaTGS with Peltier temperature control (standard); MCT (optional)
Drive	Mechanical bearing, electromagnetic drive; speed Auto, 1, 2, 3 or 4 mm/sec (DLaTGS 2.0 mm/sec, MCT 4.0 mm/sec)
Rapid scan	10 Hz (optional)
Gain switching	Auto, 1, 2, 4, 8, 16, 32, 64, 128
100%T line flatness	Within 100 ± 1.0 %T (4,000 to 700 cm-1, continuous repetitive measurement)
Sample chamber	200 mm (W) x 260 mm (D) x 185 mm
Nitrogen purge	Interferometer, sample compartment and detector
Microscope functions listed	High-sensitivity MCT detector; auto aperture, auto centering, auto X-Y stage and auto focus; memory for up to 10 sample and 2 background positions; control from the computer screen or the microscope's own keyboard
Con	
Prod	
Sup	